Search Notes					
	<b>1):                                    </b>				

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/561,028	BENYAHIA ET AL.	
Examiner	Art Unit	
Kim R. Lockett	2837	

SEARCHED			
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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